

2829

Docket No. 740756-2101

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re Patent Application of)
Shunpei YAMAZAKI et al.)
Serial No. 09/502,675) Examiner: Evan T. Pert
Filed: February 11, 2000) Group Art Unit: 2829
For: SEMICONDUCTOR DEVICE AND METHOD OF) Confirmation No. 5514
MANUFACTURING THEREFOR)

Certificate of Mailing

I hereby certify that this correspondence is being deposited with the United States Postal Service with sufficient postage for First Class Mail in an envelope addressed to: Commissioner for Patents, P. O. Box 1450, Alexandria, VA 22313-1450, on November 13, 2003.


Name: Bonnie L. Garlin

REQUEST FOR ACKNOWLEDGMENT OF
INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
Alexandria, VA 22313-1450


Sir:

Information Disclosure Statements with Forms PTO-1449 were filed in the above-identified patent application on April 10, 2002 and September 3, 2002. Applicants have not yet received back from the Examiner a copy of the Forms PTO-1449 initialed to acknowledge the fact that the Examiner has considered the cited disclosed information.

The Examiner is requested to initial and return to the undersigned a copy of the subject Forms PTO-1449.

Should there be any questions concerning this communication, please telephone the undersigned at the number set forth below.

Respectfully submitted,


Jeffrey L. Costellia
Registration No. 35,483

Nixon Peabody LLP
401 9th Street, N.W.
Suite 900
Washington, DC 20004-2128
(202) 585-8000
Fax: (202) 585-8080

Please type a plus sign (+) inside this box → [+]

NOV 17 2003

PTO/SB/08A (08-00)

Approved for use through 10/31/2002. OMB 0651-0031

U.S. Patent and Trademark Office: U.S. DEPARTMENT OF COMMERCE

Under the Paperwork Reduction Act of 1995, no persons are required to respond to a collection of information unless it contains a valid OMB control number.

Substitute for form 1449A/PTO INFORMATION DISCLOSURE STATEMENT BY APPLICANT (use as many sheets as necessary)				Complete if Known	
				Application Number	09/502,675
				Filing Date	September 3, 2002
				First Named Inventor	Shunpei YAMAZAKI
				Group Art Unit	2829
				Examiner Name	Evan T. PERT
Sheet	1	of	1	Attorney Docket Number	740756-2101

U.S. PATENT DOCUMENTS						
Examiner Initials [*]	Cite No. ¹	U.S. Patent Document		Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear
		Number	Kind Code ² (if known)			
		6,144,082		Yamazaki et al.	11/07/2000	
		6,201,281	B1	Miyazaki et al.	03/13/2001	

FOREIGN PATENT DOCUMENTS								
Examiner Initials [*]	Cite No. ¹	Foreign Patent Document			Name of Patentee or Applicant of Cited Document	Date of Publication of Cited Document MM-DD-YYYY	Pages, Columns, Lines, Where Relevant Passages or Relevant Figures Appear	T ⁶
		Office ³	Number ⁴	Kind Code ⁵ (if known)				

OTHER PRIOR ART – NON PATENT LITERATURE DOCUMENTS				
Examiner Initials*	Cite No. ¹	Include name of the author (in CAPITAL LETTERS), title of the article (when appropriate), title of the item (book, magazine, journal, serial, symposium, catalog, etc.), date, page(s), volume-issue number(s), publisher, city and/or country where published.	T ²	

Examiner Signature	Date Considered
--------------------	-----------------

*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609. Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

¹ Unique citation designation number. ² See attached Kinds of U.S. Patent Documents. ³ Enter Office that issued the document, by the two-letter code (WIPO Standard ST.3). ⁴ For Japanese patent documents, the indication of the year of the reign of the Emperor must precede the serial number of the patent document. ⁵ Kind of document by the appropriate symbols as indicated on the document under WIPO Standard ST.16 if possible. ⁶ Applicant is to place a check mark here if English language Translation is attached.

¹ Unique citation designation number. ² Applicant is to place a check mark here if English language Translation is attached.

Burden Hour Statement: This form is estimated to take 2.0 hours to complete. Time will vary depending upon the needs of the individual case. Any comments on the amount of time you are required to complete this form should be sent to the Chief Information Officer, U.S. Patent and Trademark Office, Washington, DC 20231. DO NOT SEND FEES OR COMPLETED FORMS TO THIS ADDRESS. SEND TO: Commissioner for Patents, Washington, DC 20231.

NVA238742.1

9/3/02

Form PTO-1449
(Rev. 8-83)

U.S. Department of Commerce
Patent and Trademark Office

Atty Docket 0756-2101

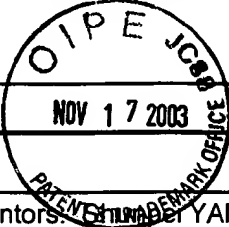
Serial No. 09/502,675

INFORMATION DISCLOSURE STATEMENT

Applicants: Shunpei YAMAZAKI et al.

Filing Date: February 11, 2000

Group Art Unit: 2812



OTHER DOCUMENT

(Including Author, Title, Date, Pertinent Pages, Etc.)

Examiner
Initial

Inventors: Shunpei YAMAZAKI et al., "Semiconductor Device and Fabrication Method Thereof" Filing Date: July 5, 2000, Specifications and Drawings for Application Serial No. 09/610,217

Inventors: Shunpei YAMAZAKI et al., "Semiconductor Device and Manufacturing Method Thereof" Filing Date: July 6, 2000, Specifications and Drawings for Application Serial No. 09/610,753

Inventor: Shunpei YAMAZAKI, "Semiconductor Device and Method of Fabricating the Same" Filing Date: December 23, 1999, Specifications and Drawings for Application Serial No. 09/471,359

Inventor: Shunpei YAMAZAKI, "Semiconductor Device and Fabrication Method Thereof" Filing Date: February 22, 2000, Specifications and Drawings for Application Serial No. 09/510,734

Inventor: Shunpei YAMAZAKI, "Method for Manufacturing an Electrooptical Device" Filing Date: March 22, 2000, Specifications and Drawings for Application Serial No. 09/533,175

Inventor: Shunpei YAMAZAKI, "Semiconductor Device and Method of Manufacturing the Same" Filing Date: February 7, 2000, Specifications and Drawings for Application Serial No. 09/498,646

Examiner

Date Considered

*EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.

04/04/2002 4/10/02